

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BAK, BONG-GIL	
		Examiner HUY T. NGUYEN	Art Unit 2621	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,438,423 A	08-1995	Lynch et al.	386/109
*	B	US-6,311,011 B1	10-2001	Kuroda, Masahiro	386/46
*	C	US-7,272,300 B2	09-2007	Srinivasan et al.	386/95
*	D	US-4,982,390	01-1991	Tanaka, Yoichiro	369/83
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